

In the United States Patent and Trademark Office

In re the application of
Lee D. Whetsel

Serial No.: 09/955,542

Filed: 9/18/2001

Title: Low Power Scan & Delay Test Method and Apparatus



TI-31727

Art Unit: 2133

Examiner: J. Kerveros Technology Center 2100

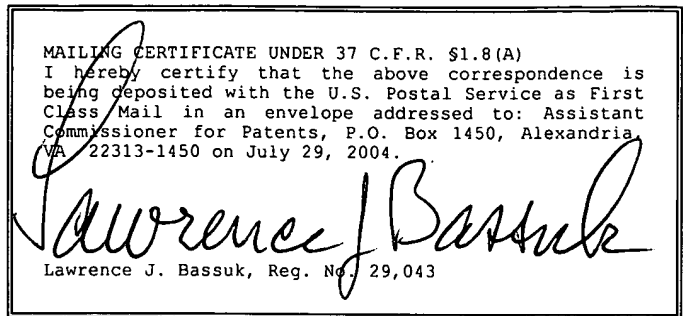
RECEIVED

AUG 09 2004

July 29, 2004

Asst. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

Dear Sir:



Transmitted herewith is an amendment in this application.

The fee has been calculated as shown below.

| CLAIMS AS AMENDED | | | | | | |
|---|---|-------|---|------------------|----------|-------------------|
| | CLAIMS REMAINING AFTER AMENDMENT | | HIGHEST NUMBER PREVIOUSLY PAID FOR | PRESENT EXTRA | RATE | ADDITIONAL FEE |
| Total Claims | 7 | Minus | 20 | = 0 | x \$18 = | \$ 0 |
| Ind. Claims | 1 | Minus | 4 | = 0 | x \$86 = | \$ 0 |
| TOTAL ADDITIONAL FEE FOR THIS AMOUNT | | | | | | \$ 0 |

Under 37 C.F.R. § 1.16(k) please charge the total additional fee, and any further fees, or credit overpayment to Deposit Account No. 20-0668, of Texas Instruments Incorporated.

Respectfully submitted,

Lawrence J. Bassuk

Lawrence J. Bassuk
Reg. No. 29,043
Attorney for Applicant

Texas Instruments Incorporated
P.O. Box 655474, M/S 3999
Dallas, Texas 75265
(972) 917-4418